

PATENT

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Application of:

Jeffery N. Gleason

Serial No.: Not Yet Assigned

Filed: October 20, 2003

For: USING STABILIZERS IN
ELECTROLESS SOLUTIONS TO INHIBIT
PLATING OF FUSES

Confirmation No.: Unknown

Examiner: Unknown

Group Art Unit: Unknown

Attorney Docket No.: 2269-5157.1US
(01-1004.01/US)

COPY

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Date of Deposit with USPS: October 20, 2003

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INFORMATION DISCLOSURE STATEMENT

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Sir:

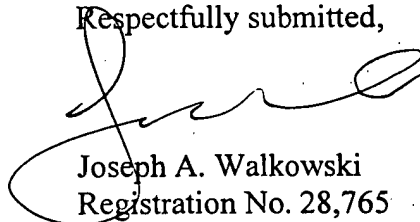
The present application is a divisional of application Serial No. 10/154,755, filed May 24, 2002, pending.

Pursuant to M.P.E.P. 2001.06(b), the Examiner is respectfully requested to consider the information of record in the prior application, and to confirm in the first Office Action on the merits that such art has in fact been reviewed. A PTO-1449 or PTO/SB/08 form listing all of the information of record in the prior application is enclosed herewith.

Attorney Docket No. 2269-5157.1US

This Information Disclosure Statement is filed within three (3) months of the filing date of the above-identified application, and no certification pursuant to 37 C.F.R. § 1.97(c) or a fee pursuant to 37 C.F.R. 1.17(p) is required.

Respectfully submitted,



Joseph A. Walkowski
Registration No. 28,765
Attorney for Applicant
TRASKBRITT
P.O. Box 2550
Salt Lake City, Utah 84110-2550
Telephone: 801-532-1922

Date: October 20, 2003
JAW/dlm:ljb
Enclosures: Form PTO-1449 or PTO/SB/08

Document in ProLaw

Form PTO-1449

Docket Number (Optional)
5157.1US (01-1004.01/US)Application Number
Not yet assignedINFORMATION DISCLOSURE CITATION
IN AN APPLICATION

Applicant Jeffery N. Gleason

Filing Date October 20, 2003

Group Art Unit Unknown

Use several sheets if necessary)

U.S. PATENT DOCUMENTS

EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
	5,203,911	04/1993	Sricharoenchaikit et al.			
	5,258,062	11/1993	Nakazawa et al.			
	6,043,966	03/2000	Krueger et al.			
	6,235,557 B1	05/2001	Manley			
	6,277,674 B1	08/2001	Wang et al.			
	6,300,242 B1	10/2001	Ueda et al.			
	6,323,534 B1	11/2001	Marr et al.			
	6,335,626 B1	01/2002	Motulla			
	2002/0011666 A1	01/2002	Tandy			
	2003/0003703 A1	01/2003	Barth et al.			

FOREIGN PATENT DOCUMENTS

	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	Translation	
						YES	NO

OTHER DOCUMENTS

(Including Author, Title, Date, Pertinent Pages, Etc.)

		HENDERSON, Christopher L., et al., "The Behavior and Testing Implications of CMOS IC Open Circuits," Proc. International Test Conference, (1991), pp. 1-11.
		INCO Newsletter, "Nickel Currents," Vol. 6, No. 2, (1999), pp. 1-4.
		Cascade Microtech Technical Data Sheet, "Challenges of Conventional Wafer Probing," (2002).

EXAMINER

DATE CONSIDERED

EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP § 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to the applicant.